

Notice of References Cited	Application/Control No. 10/602,629	Applicant(s)/Patent Under Reexamination WATANABE, SHIGEKI	
	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,150,248	09-1992	Alfano et al.	398/147
*	B	US-6,801,349	10-2004	Kim et al.	359/108
	C	US-			
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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